



Docket No.: M4065.0315/P315-  
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:  
Lingyi A. Zheng et al.

Application No.: 09/651,998

Filed: August 31, 2000

For: METHOD AND STRUCTURE FOR  
REDUCING LEAKAGE CURRENT IN  
CAPACITORS

Group Art Unit: 2812

Examiner: H. Tsai

RECEIVED  
SEP - 7 2001  
TC 2800 MAIL ROOM

#8/Response  
9/12/01  
V. Vannal

RESPONSE

Commissioner for Patents  
Washington, DC 20231

Dear Sir:

In response to the Office Action dated June 7, 2001 (Paper No. 5), Applicants have the following remarks:

REMARKS

The application has been carefully reviewed in light of the Office Action dated June 7, 2001. Claims 1-59 are pending in this case.

Claims 1-59 stand rejected under 35 U.S.C. § 103(a) as being unpatentable over Cho (U.S. Patent No. 6,096,592) or Kamiyama (U.S. Patent No. 5,254,505) in view of Miner et al. (U.S. Patent No. 6,114,258) and Schuegraf et al. (U.S. Patent No. 5,264,865). Applicants respectfully traverse the rejection and request reconsideration.

Claim 1 recites contacting a dielectric layer "with hydrogen, oxygen and nitrous oxide gases so as to form an oxidation layer over said" dielectric layer. It is the forming of